

## Paper List

*January –December, 2024*

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- E2024-1(L)     Nanoshell Formation at the Electrically Charged Gas–Water Interface of Collapsing Microbubbles: Insights from Atomic Force Microscopy Imaging  
The Journal of Physical Chemistry Letters, Vol.15, Issue 1, pp. 220–225, (2024), January 11, 2024.  
Masayoshi Takahashi, Yasuyuki Shirai, and Shigetoshi Sugawa  
<https://doi.org/10.1021/acs.jpcllett.3c03314>
- E2024-2(F)     Threshold voltage uniformity improvement by introducing charge injection tuning for low-temperature poly-Si thin film transistors with metal/oxide/nitride/oxide/silicon structure     Japanese Journal of Applied Physics, Vol.63, Number 2, 02SP51, (2024), Special Issue on Solid State vices and Materials 2023 (SSDM2023), January 17, 2024.  
Tetsuya Goto, Tomoyuki Suwa, Keita Katayama, Shu Nishida, Hiroshi Ikenoue and Shigetoshi Sugawa  
<https://doi.org/10.35848/1347-4065/ad184d>
- E2024-3(F)     [Invited Paper]  
A High SNR Global Shutter CMOS Image Sensor Technology for High Precision Absorption Imaging Applications  
ITE Transactions on Media Technology and Applications, (2024), Vol.12, Issue 2, pp.167-174, 1 April 2024.  
Tetsu Oikawa, Rihito Kuroda, Aoi Hamaya, Yoshinobu Shiba, Takafumi Inada, Yushi Sakai, Yasuyuki Shirai, Shigetoshi Sugawa  
<https://doi.org/10.3169/mta.12.167>
- E2024-4(C)     Impedance Measurement Platform for Statistical Capacitance and Current Characteristic Measurements of Arrayed Cells with Atto-order Precision  
2024 IEEE 36th International Conference on Microelectronic Test Structures, 4.2, April 15-18, 2024, Edinburgh, UK  
Koga Saito, Tatsuhiko Suzuki, Hidemi Mitsuda, Tsubasa Nozaki, Takezo Mawaki, and Rihito Kuroda  
<https://doi.org/10.1109/ICMTS59902.2024.10520692>
- E2024-5(W)     [Invited]  
Dynamics at the Gas-Water Interface of Collapsing Microbubbles:An Exciting Reaction Field-  
The 8th International Symposium on Plasmas & Fine Bubbles (8<sup>th</sup> ISPFB 2024), Shanghai, China(Online), May 25, 2024.  
Masayoshi Takahashi

- E2024-6(W) [Invited] Special Talk Session  
 Role of academia in the 2-nm-node era and beyond- There are still many things to research at academia! or? -  
 2024 International Conference on Solid State Devices and Materials (SSDM2024), Special Talk Session, Himeji, Sep.1, 2024  
 Rihito Kuroda, Kazuya Masu, Seiichi Miyazaki, Akira Toriumi, and Tomonari Yamamoto
- E2024-7(C) Evaluation of Metal Contamination Behavior on Silicon Wafer Surfaces Rinsed with Deionized Water Containing pg/L-Level Impurities  
 PRiME 2024(PACIFIC RIM MEETING ON ELECTROCHEMICAL AND SOLID-STATE SCIENCE), Abs.G02-2271, Honolulu, October 10, 2024  
 Kyohei Tsutano, Takezo Mawaki, Yasuyuki Shirai, and Rihito Kuroda  
<https://doi.org/10.1149/MA2024-02312271mtgabs>
- E2024-8(P) Evaluation of Metal Contamination Behavior on Silicon Wafer Surfaces Rinsed with Deionized Water Containing pg/L-Level Impurities  
 ECS Transactions, Volume 114, Number 1, pp27-33, 2024  
 Kyohei Tsutano, Takezo Mawaki, Yasuyuki Shirai and Rihito Kuroda  
<https://doi.org/10.1149/11401.0027ecst>
- E2024-9(F) Impact of Bulk Nanobubble Water on a TiO<sub>2</sub> Solid Surface: A Case Study for Medical Implants  
 Langmuir, Vol.40, Issue 49, 25950-25956, (2024), November 25, 2024.  
 Masayoshi Takahashi, Masahiro Nakazawa, Takahiro Nishimoto, Mitsuyuki Odajima, Yasuyuki Shirai, and Shigetoshi Sugawa  
<https://doi.org/10.1021/acs.langmuir.4c03339>
- E2024-10(C) High-Precision Mass Transfer Technology for Transparent Flexible Micro-LED Displays  
 Proceedings of the International Display Workshops, (2024), FMC6-1L, Sapporo, December 5, 2024  
 Kengo Shima, Tatsuya Ishida, Koichi Kajiyama, Yasuyuki Shirai, Takahiro Ishinabe
- E2024-11(C) [Best Paper Award]  
 Evaluation of Metal Contamination Behavior on Silicon Dioxide Surface Rinsed with Deionized Water Containing Ultra-Trace Metal in Single-Wafer Cleaning Process  
 International Symposium on Semiconductor Manufacturing 2024, (2024), YE-018, December 10, Tokyo  
 Kyohei Tsutano, Takezo Mawaki, Yasuyuki Shirai and Rihito Kuroda  
<https://doi.org/10.1109/ISSM64832.2024.10874881>